


<b>Search Notes</b>  	<b>Application/Control No.</b>  10624759	<b>Applicant(s)/Patent Under Reexamination</b>  WEN ET AL.
	<b>Examiner</b>  Ahn, Sangwoo	<b>Art Unit</b>  2166

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST updated (see search history printout(s))	12/5/2007	SA
Review of previously applied art	5/11/2009	SA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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